

DETAILED ACTION

Continued Examination Under 37 CFR 1.114

1. A request for continued examination under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action has been withdrawn pursuant to 37 CFR 1.114. Applicant's submission filed on 03-11-09 has been entered.

Amendment

2. Acknowledgement is made of Amendment filed 03-11-09.
3. Claims 5, 24 and 52 are amended.
4. Claim 1 has been canceled.

EXAMINER'S AMENDMENT

5. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview response from Attorney Janet Cord on 03-16-2009.

For Claims 34-51:

-- 34-51 (**Canceled**) --

Allowable Subject Matter

6. Claims 2-33 and 52-56 are allowed.
7. The following is a statement of reasons for the indication of allowable subject matter:

Claims 2-33 and 52-56 are allowable because the prior art of record neither anticipates nor renders obvious the limitations of the base claim 52 in combination as claimed, including:

wherein a base electrode formed by the conductor layer is provided on the substrate, on which base electrode layers belonging to the component and including an upper cover-electrode are arranged, wherein the component is applied by thin-film technology, and the conductor layer is smoothed at least on the location of the thin-film component, wherein the smoothed conductor layer over surface areas having the dimensions of $20 \times 20 \mu\text{m}^2$ (micro-roughness), exhibits a maximum mean surface roughness of 10nm and a contact layer is applied by thin-film technology between the smoothed, optionally reinforced, conductor layer and the superimposed thin-film layers of the thin-film component, which contact layer is physically or chemically adsorbed directly on the surface of the base electrode, wherein the contact layer is arranged to passivate the conductor layer, and the contact layer further constitutes an electric contacting-

promoting layer and an adhesion-improving layer for enhancing the electric contact between the conductor layer and the thin film component and for stabilizing the adherence of the thin film component on the conductor layer, respectively.

After carefully review the specification and the claims in the application and art search, considering what is claimed as a whole that the aforementioned limitations are believed to render said claim 52 and all claims dependent thereof patentable over art of record.

8. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

9. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Xiaoliang Chen whose telephone number is 571-272-9079. The examiner can normally be reached on 8:00-5:00 (EST).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Dean Reichard can be reached on 571-272-2800, ext 31. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

/Dean A. Reichard/
Supervisory Patent Examiner, Art Unit 2841

Xiaoliang Chen
Examiner
Art Unit 2809